

Notice of References Cited	Application/Control No. 10/580,510		Applicant(s)/Patent Under Reexamination LIETZ ET AL.	
	Examiner RYAN M. STIGLIC		Art Unit 2111	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,389,496 B1	05-2002	Matsuda, Junichi	710/316
*	B	US-6,445,711 B1	09-2002	Scheel et al.	370/402
*	C	US-2002/0167953 A1	11-2002	Scheel et al.	370/401
*	D	US-6,519,671 B1	02-2003	Kondou et al.	710/311
*	E	US-2003/0053466 A1	03-2003	Bizet et al.	370/401
*	F	US-2003/0188081 A1	10-2003	Fukushima et al.	710/314
*	G	US-7,007,078 B2	02-2006	Matsuda, Junichi	709/220
*	H	US-7,043,594 B2	05-2006	Fukushima et al.	710/314
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Texas Instruments; "TSB12C01A Data Manual"; Texas Instruments; Document No. SLLS219B; November 1996; pages 1-59.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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